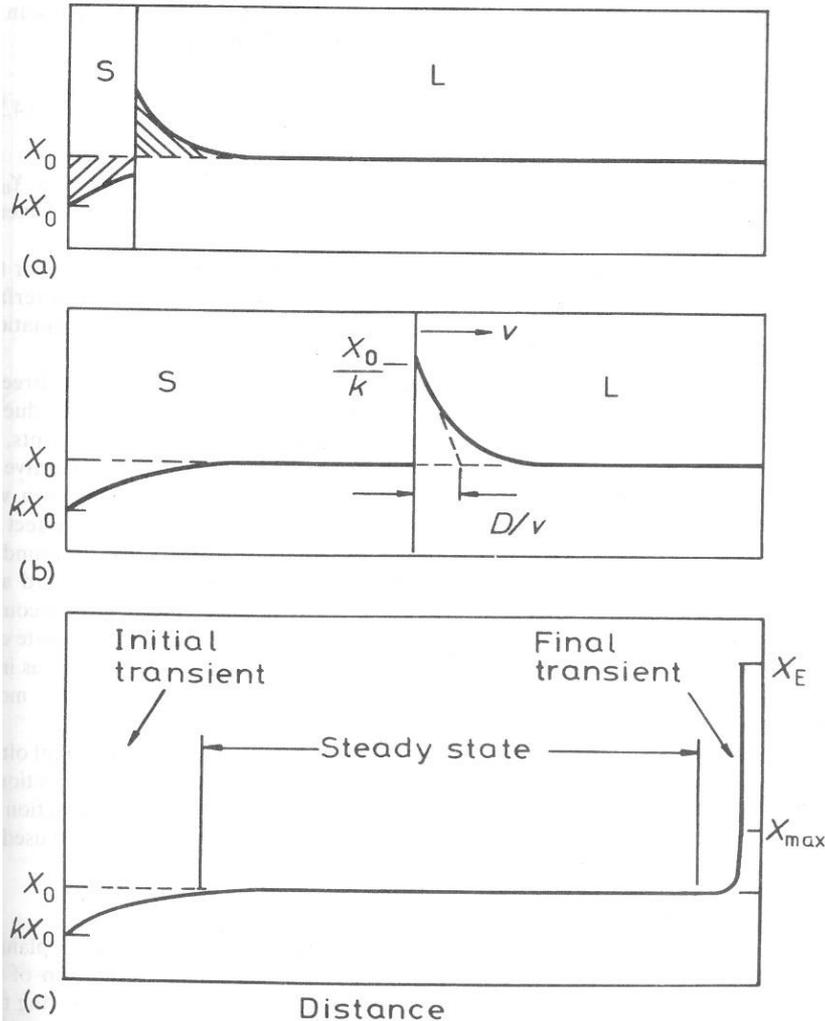


# 4.3 Alloy Solidification

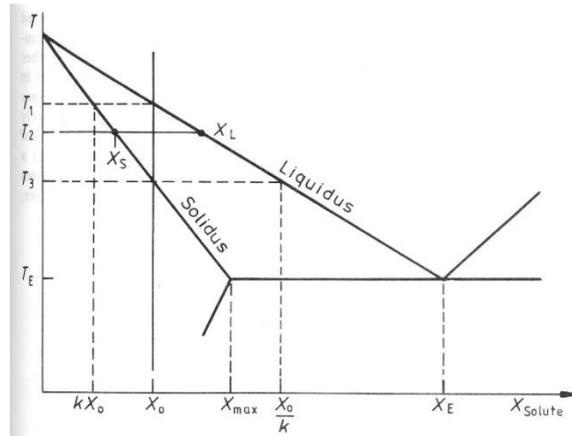
## 3. No diffusion in solid, diffusional mixing in the liquid



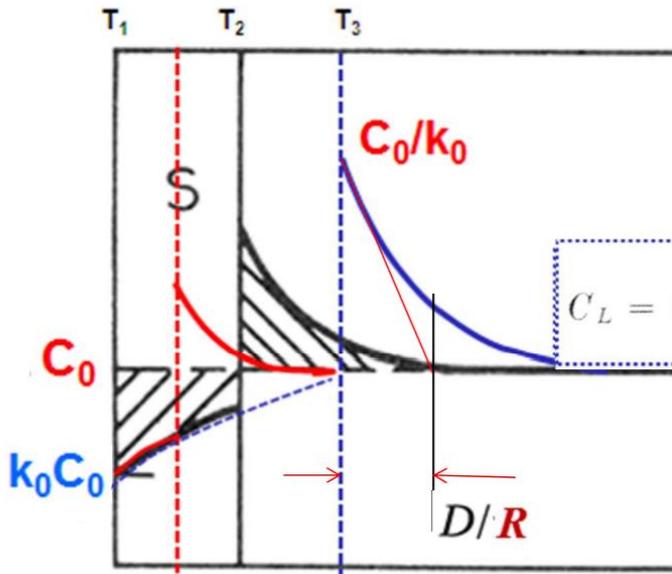
- ✓ Solute rejected from solid → diffuse into liquid with limitation
- ✓ Rapid build up solute in front of the solid → rapid increase in the composition of solid forming (initial transient)
- ✓ If it solidifies at a constant rate,  $v$ , then a steady state is finally obtained at  $T_3$
- ✓ liquid :  $X_0/k$  , solid :  $X_0$

# 4.3 Alloy Solidification (diff. mixing in liq.)

## I. Initial transient



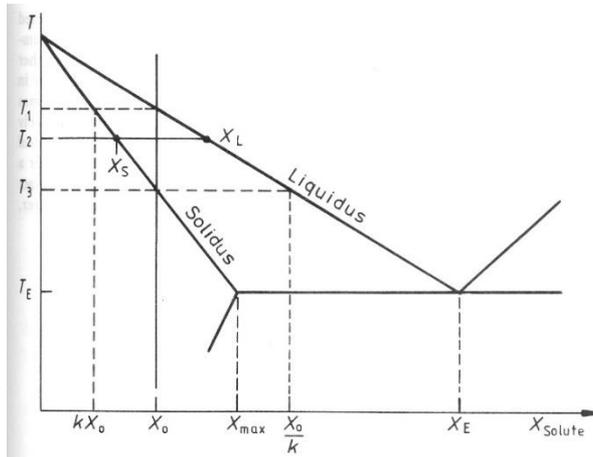
Interface temperature



- ✓  $T_1 < T < T_3$
- ✓ First solid:  $kX_0$
- ✓ Solute rejected from solid  $\rightarrow$  diffuse into liquid with limitation
- ✓ Rapid build up solute in front of the solid  $\rightarrow$  rapid increase in the composition of solid forming (initial transient)
- ✓ Solute rejected from solid to liquid, and increase the liquid concentration
- ✓ Two shaded areas are equal

# 4.3 Alloy Solidification (diff. mixing in liq.)

## II. Steady State



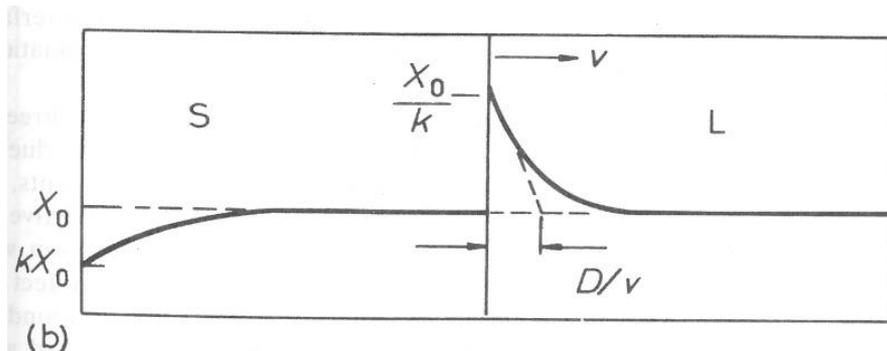
✓  $T = T_3$

✓ If it solidifies at a constant rate,  $v$ , then a steady state is finally obtained at  $T_3$

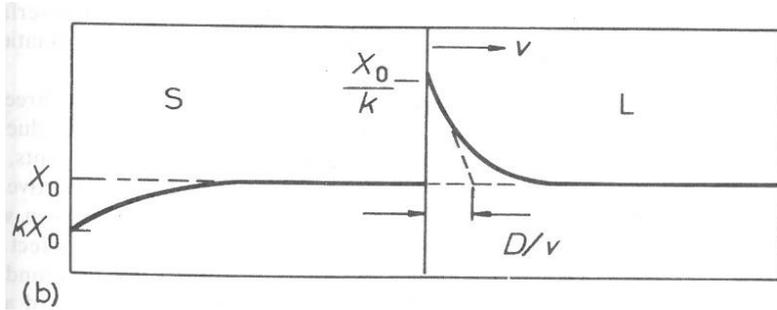
✓ liquid :  $X_0/k$  , solid :  $X_0$

✓ Rate of solute diffuses down (away from the interfaces) = Rate of solute is rejected from the solidifying liquids

$$-D \frac{dC_L}{dX} = v(C_L - C_S)$$



# 4.3 Alloy Solidification (diff. mixing in liq.)



$$X_L = X_0 \left[ 1 + \frac{1-k}{k} \exp\left(-\frac{x}{D/v}\right) \right]$$

$$(x = 0, \quad X_L = \frac{X_0}{k}) \quad (X_0 = X_S)$$

Slope of the curve at  $x = 0$

$$\begin{aligned} \left. \frac{dX_L}{dx} \right|_{x=0} &= \frac{1-k}{k} X_0 \left[ -\frac{1}{D/v} \right] \exp\left(-\frac{x}{D/v}\right) \Big|_{x=0} \\ &= -\left( \frac{X_L - X_0}{d} \right) = \frac{1-k}{k} X_0 \left[ -\frac{1}{D/v} \right] \end{aligned}$$

$$\therefore d = D/v$$

Characteristic distance:  
excess conc. falls to 1/e

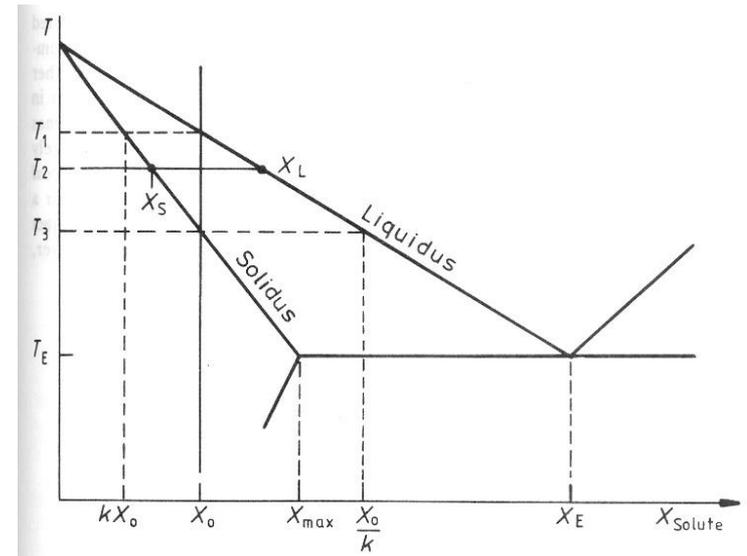
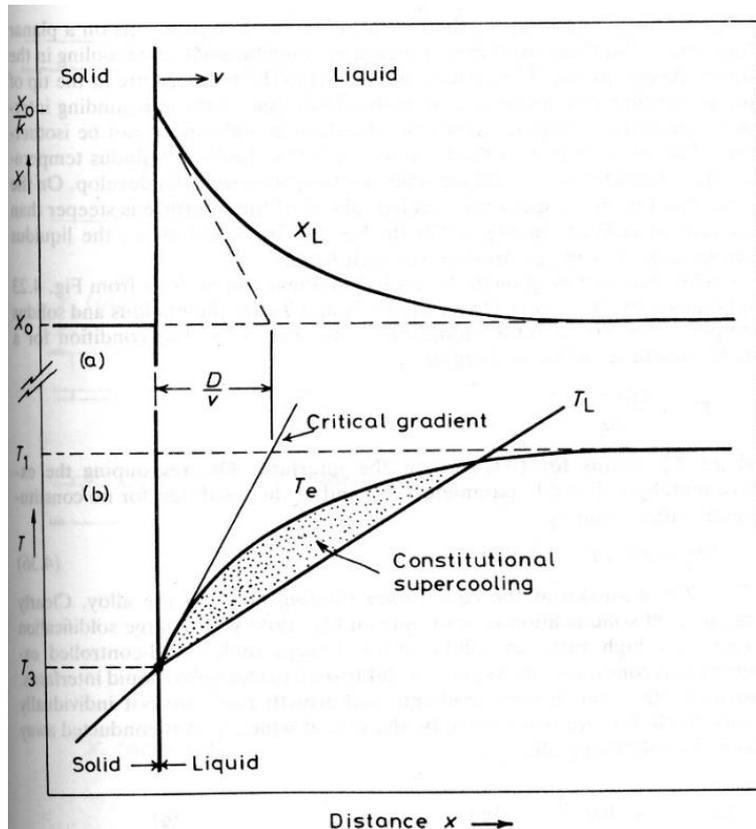
$$x = D/v \rightarrow \exp(-1) \rightarrow 1/e$$

## III. Final transient

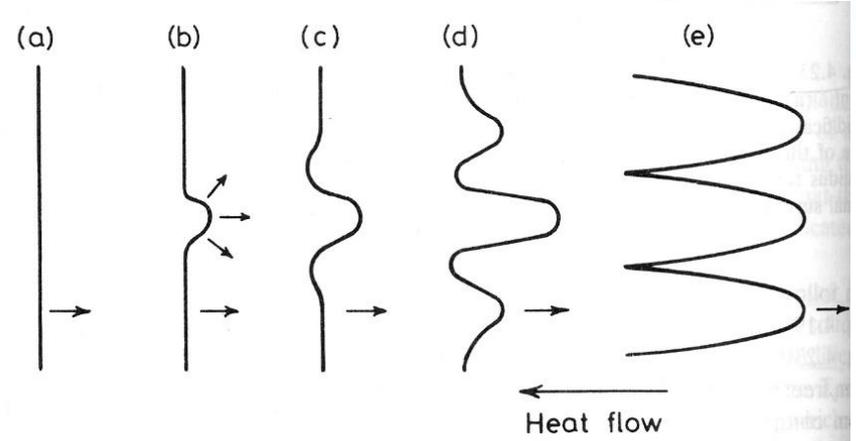
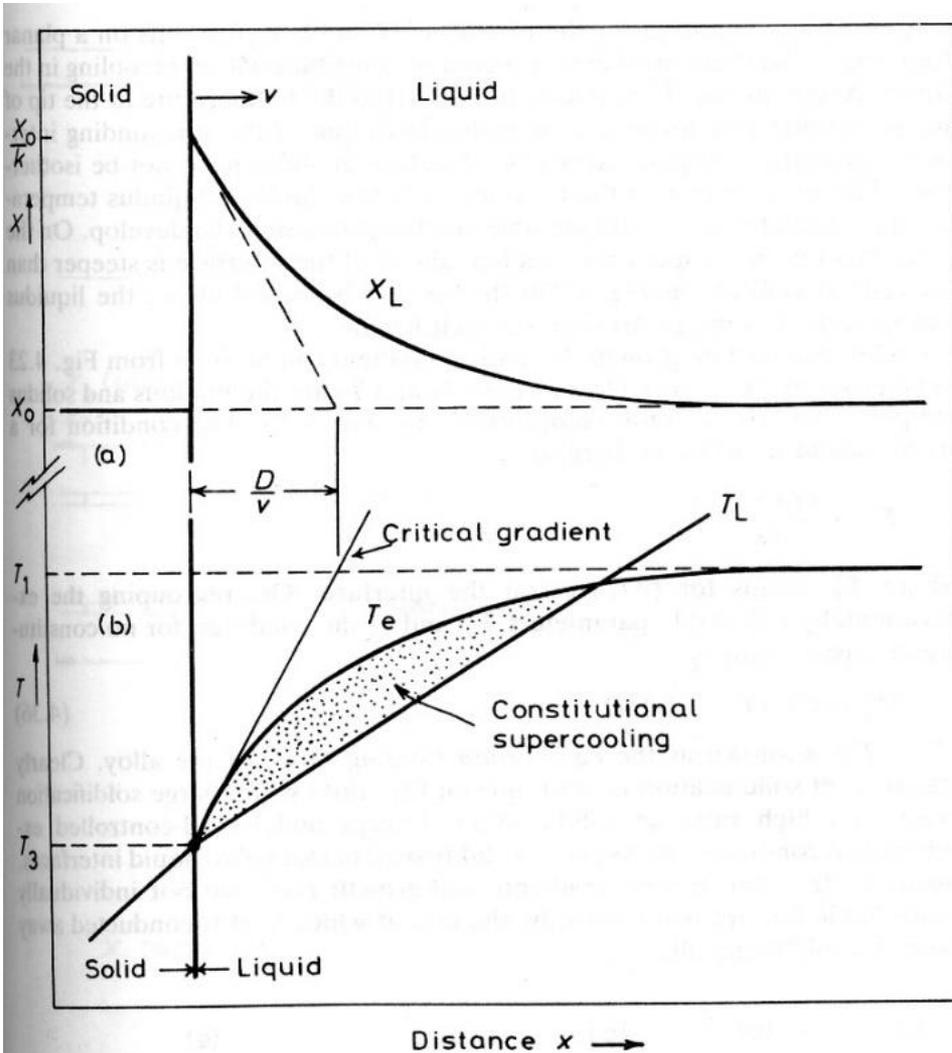
If solid/liquid interface in within  $\sim D/v$  of the end of the bar  
 $\rightarrow$  compressed to final transient (eutectic formation)

# 4.3 Cellular and dendritic solidification

- Solute diffusion into the liquid during solidification in alloy
- ~ similar to the conduction of latent heat in pure metal
- possible to break up the planar front into dendrites.
- complicated by the possible temp. gradient in the liquid.

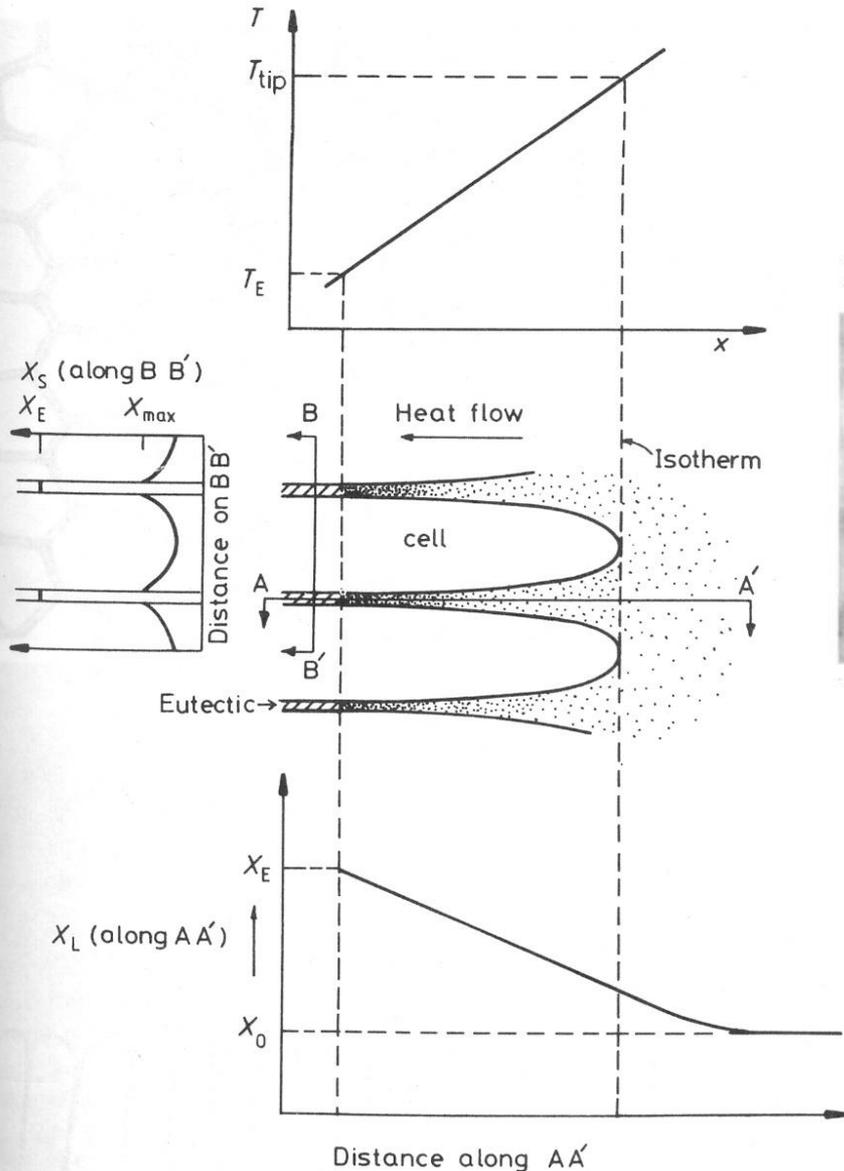


# 4.3 Cellular and dendritic solidification

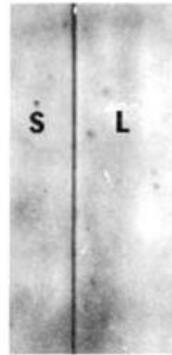


$$\left. \frac{dX_L}{dX} \right|_{X=0} = \frac{T_1 - T_2}{D/v}$$

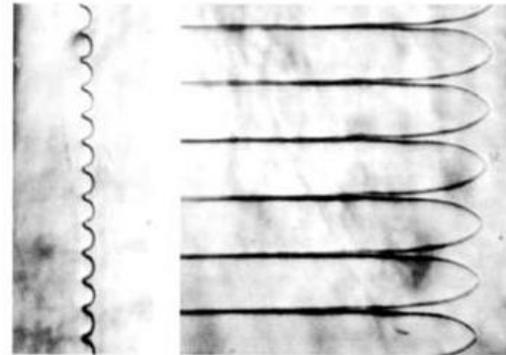
# 4.3 Cellular and dendritic solidification



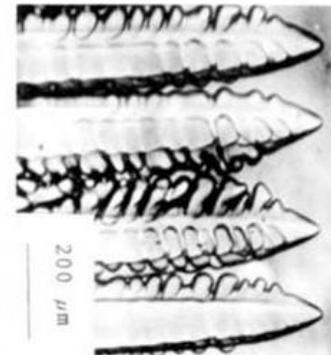
planar



cellular

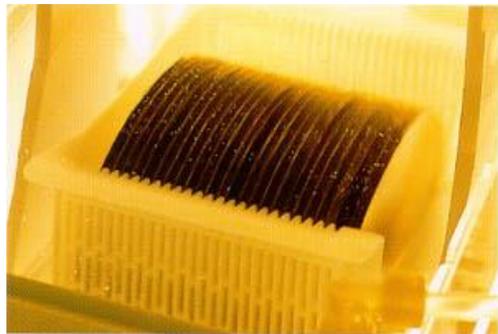
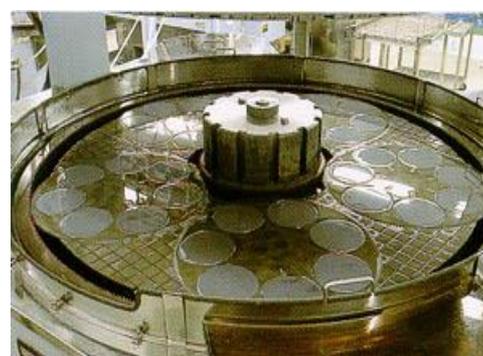
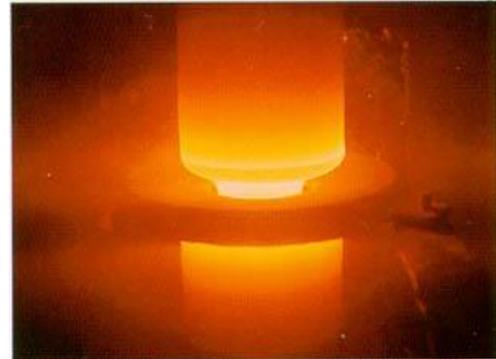
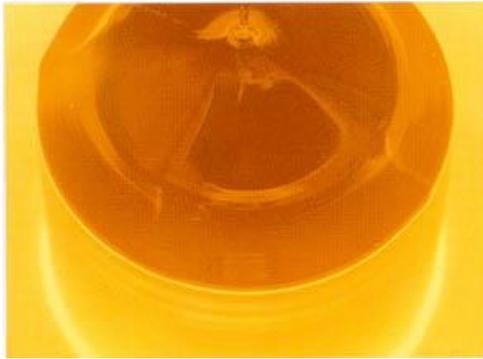


dendritic



Increasing growth rate  $\longrightarrow$

# Wafer Production



|             |           |           |
|-------------|-----------|-----------|
| Poly-Si rod | CZ Growth | FZ Growth |
| Slicing     | Lapping   | Polishing |
| Cleaning    | Wafer     |           |

# Dopant Behavior During Crystal Growth

- Dopants are added to the melt to provide a controlled N or P doping level in the wafers.
- However, the dopant incorporation process is complicated by dopant segregation.

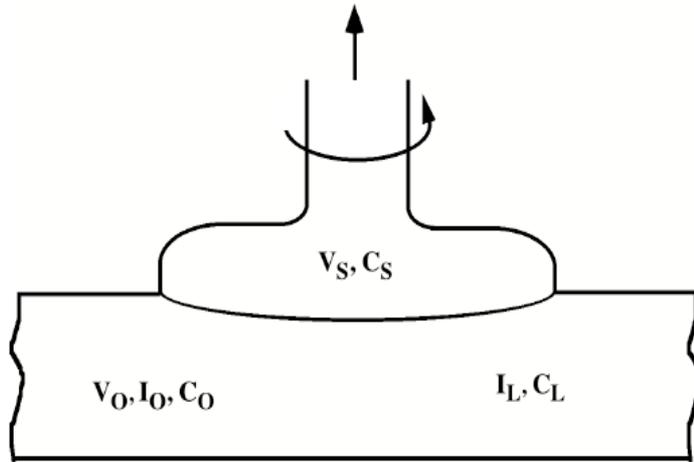
| Dopant | $k_0$                |
|--------|----------------------|
| As     | 0.3                  |
| Bi     | $7 \times 10^{-4}$   |
| C      | 0.07                 |
| Li     | $10^{-2}$            |
| O      | 0.5                  |
| P      | 0.35                 |
| Sb     | 0.023                |
| Al     | $2.8 \times 10^{-3}$ |
| Ga     | $8 \times 10^{-3}$   |
| B      | 0.8                  |
| Au     | $2.5 \times 10^{-5}$ |

$$k_0 = \frac{C_S}{C_L} \quad (11)$$

- Most  $k_0$  values are  $<1$  which means the impurity prefers to stay in the liquid.
- Thus as the crystal is pulled,  $N_S$  will increase.

# Dopant Behavior During Crystal Growth

- If during growth, an additional volume  $dV$  freezes, the impurities incorporated into  $dV$  are given by



$$dI = -k_O C_L dV = -k_O \frac{I_L}{V_O - V_S} dV \quad (12)$$

$$\therefore \int_{I_O}^{I_L} \frac{dI}{I} = -k_O \int_0^{V_S} \frac{dV}{V_O - V_S} \quad (13)$$

$$\therefore I_L = I_O \left(1 - \frac{V_S}{V_O}\right)^{k_O} \quad (14)$$

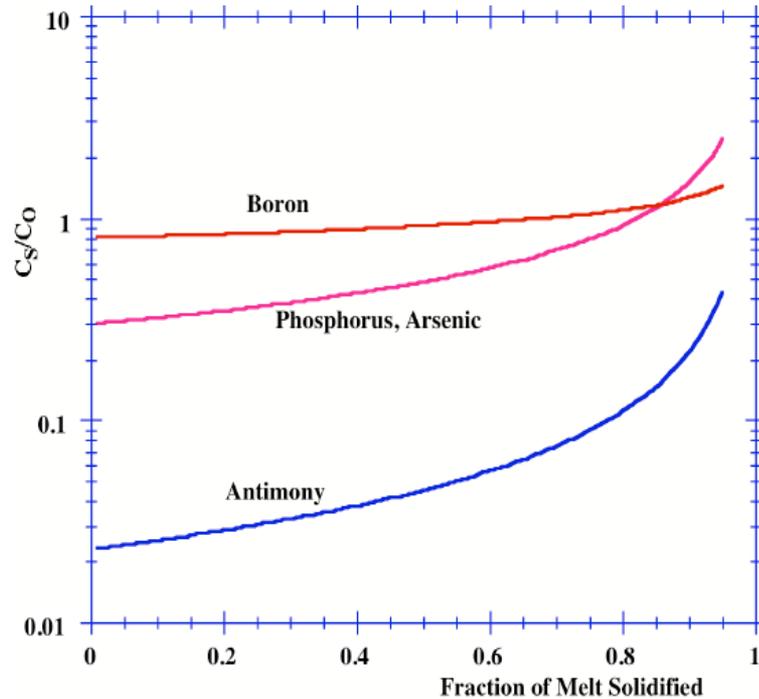
- We are really interested in the impurity level in the crystal ( $C_S$ ), so that

$$C_S = \frac{dI_L}{dV_S} \quad (15)$$

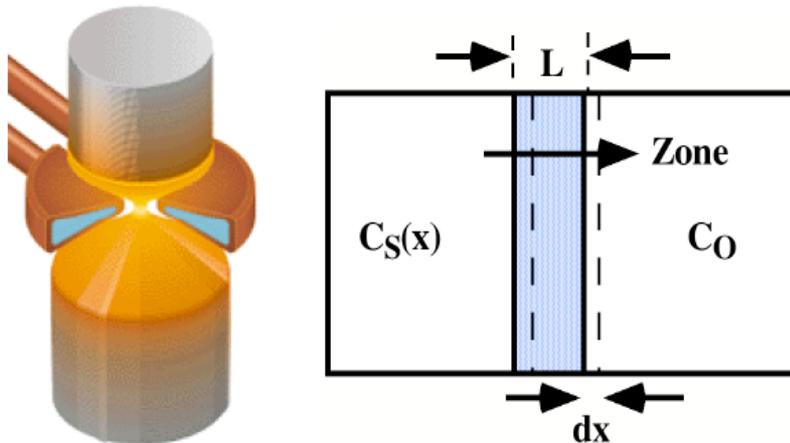
$$\therefore C_S = C_O k_O (1 - f)^{k_O - 1} \quad (16)$$

where  $f$  is the fraction of the melt frozen.

# Dopant Behavior During Crystal Growth



- Plot of Eq. (16).
- Note the relatively flat profile produced by boron with a  $k_S$  close to 1.
- Dopants with  $k_S \ll 1$  produce much more variation in doping concentration along the crystal.



- In the float zone process, dopants and other impurities tend to stay in the liquid and therefore refining can be accomplished, especially with multiple passes
- See the text for models of this process.